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Details

Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	48MHz
Connectivity	EBI/EMI, I ² C, SMBus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	40
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.65V ~ 3.6V
Data Converters	A/D 32x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-TQFP
Supplier Device Package	48-TQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8ub20f32g-a-qfp48r

2. Ordering Information

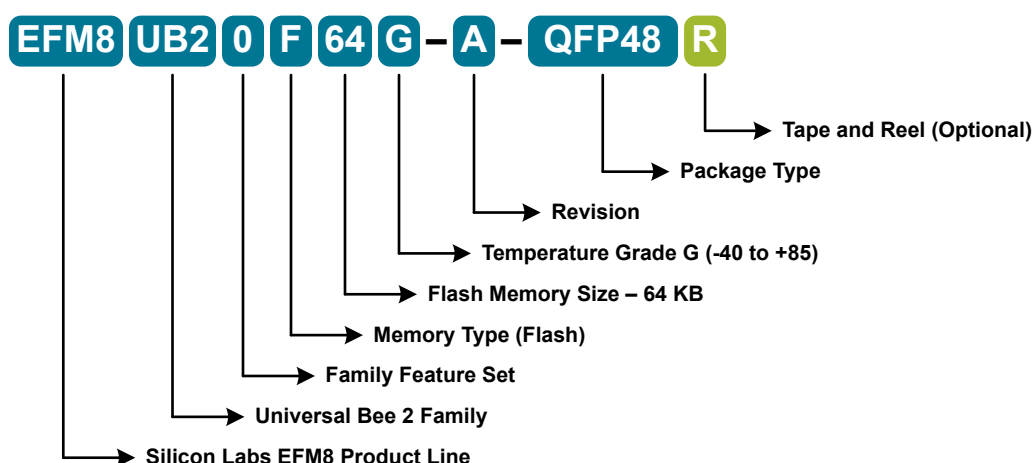


Figure 2.1. EFM8UB2 Part Numbering

All EFM8UB2 family members have the following features:

- CIP-51 Core running up to 48 MHz
- Two Internal Oscillators (48 MHz and 80 kHz)
- USB Full/Low speed Function Controller
- 5 V-In, 3.3 V-Out Regulator
- 2 SMBus/I2C Interfaces
- SPI
- 2 UARTs
- 5-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 6 16-bit Timers
- 2 Analog Comparators
- 10-bit Differential Analog-to-Digital Converter with integrated multiplexer and temperature sensor
- Pre-loaded USB bootloader

In addition to these features, each part number in the EFM8UB2 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Crystal Oscillator	External Memory Interface	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8UB20F64G-B-QFP48	64	4352	40	32	5	5	Yes	Yes	Yes	-40 to +85 °C	QFP48
EFM8UB20F64G-B-QFP32	64	4352	25	20	5	4	—	—	Yes	-40 to +85 °C	QFP32
EFM8UB20F64G-B-QFN32	64	4352	25	20	5	4	—	—	Yes	-40 to +85 °C	QFN32
EFM8UB20F32G-B-QFP48	32	2304	40	32	5	5	Yes	Yes	Yes	-40 to +85 °C	QFP48
EFM8UB20F32G-B-QFP32	32	2304	25	20	5	4	—	—	Yes	-40 to +85 °C	QFP32
EFM8UB20F32G-B-QFN32	32	2304	25	20	5	4	—	—	Yes	-40 to +85 °C	QFN32

3. System Overview

3.1 Introduction

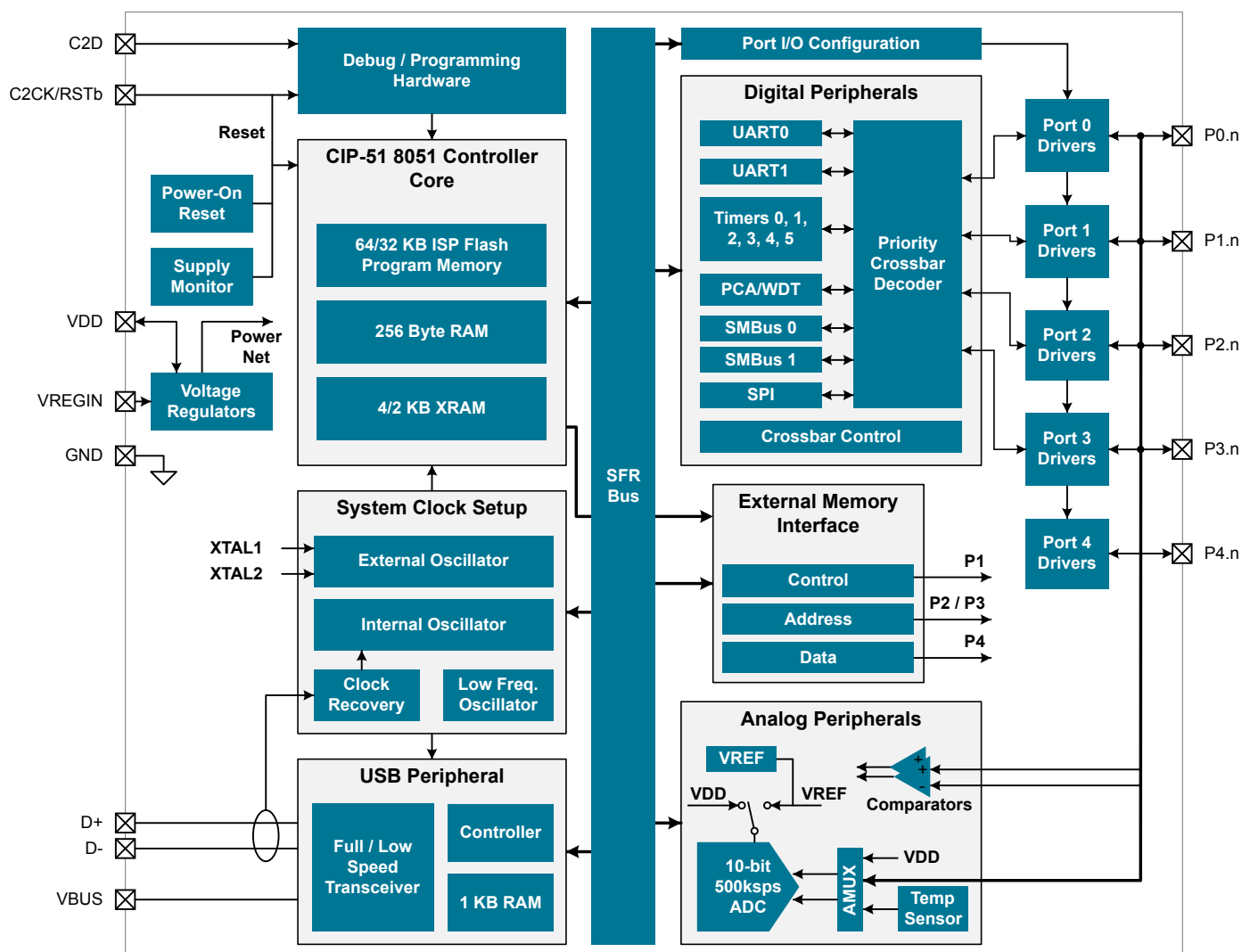


Figure 3.1. Detailed EFM8UB2 Block Diagram

This section describes the EFM8UB2 family at a high level. For more information on each module including register definitions, see the EFM8UB2 Reference Manual.

System Management Bus / I2C (SMB0 and SMB1)

The SMBus I/O interface is a two-wire, bi-directional serial bus. The SMBus is compliant with the System Management Bus Specification, version 1.1, and compatible with the I²C serial bus.

The SMBus modules include the following features:

- Standard (up to 100 kbps) and Fast (400 kbps) transfer speeds.
- Support for master, slave, and multi-master modes.
- Hardware synchronization and arbitration for multi-master mode.
- Clock low extending (clock stretching) to interface with faster masters.
- Hardware support for 7-bit slave and general call address recognition.
- Firmware support for 10-bit slave address decoding.
- Ability to inhibit all slave states.
- Programmable data setup/hold times.

External Memory Interface (EMIF0)

The External Memory Interface (EMIF) enables access of off-chip memories and memory-mapped devices connected to the GPIO ports. The external memory space may be accessed using the external move instruction (MOVX) with the target address specified in either 8-bit or 16-bit formats.

- Supports multiplexed and non-multiplexed memory access.
- Four external memory modes:
 - Internal only.
 - Split mode without bank select.
 - Split mode with bank select.
 - External only
- Configurable ALE (address latch enable) timing.
- Configurable address setup and hold times.
- Configurable write and read pulse widths.

3.7 Analog

10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 10-bit mode, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

The ADC module is a Successive Approximation Register (SAR) Analog to Digital Converter (ADC). The key features of this ADC module are:

- Up to 32 external inputs.
- Differential or Single-ended 10-bit operation.
- Supports an output update rate of 500 ksps samples per second.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- Output data window comparator allows automatic range checking.
- Two tracking mode options with programmable tracking time.
- Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Voltage reference selectable from external reference pin, on-chip precision reference (driven externally on reference pin), or VDD supply.
- Integrated temperature sensor.

3.10 Bootloader

All devices come pre-programmed with a USB bootloader. This bootloader resides in the last three pages of code flash, which includes the code security page; it can be erased if it is not needed.

The byte before the Lock Byte is the Bootloader Signature Byte. Setting this byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

When a bootloader is present, the device will jump to the bootloader vector after any reset, allowing the bootloader to run. The bootloader then determines if the device should stay in bootload mode or jump to the reset vector located at 0x0000. When the bootloader is not present, the device will jump to the reset vector of 0x0000 after any reset.

More information about the bootloader protocol and usage can be found in *AN945: EFM8 Factory Bootloader User Guide*. Application notes can be found on the Silicon Labs website (www.silabs.com/8bit-appnotes) or within Simplicity Studio by using the [Application Notes] tile.

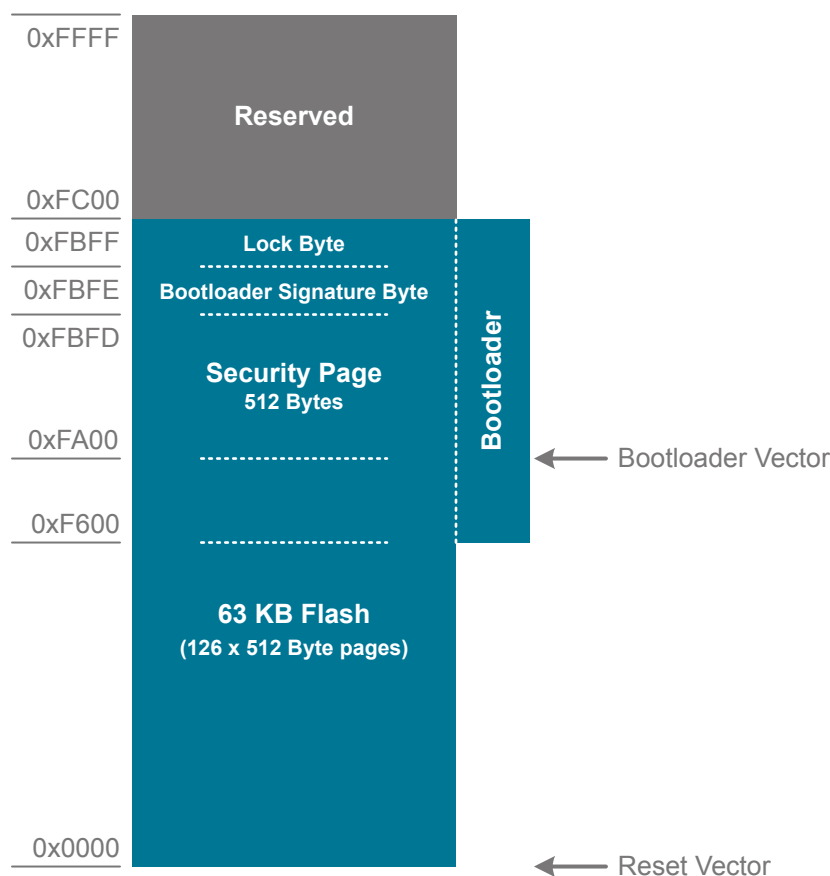


Figure 3.2. Flash Memory Map with Bootloader—64 KB Devices

Table 3.2. Summary of Pins for Bootloader Communication

Bootloader	Pins for Bootload Communication
UART	TX – P0.4
	RX – P0.5
USB	VBUS
	D+
	D-

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Note: <ol style="list-style-type: none"> 1. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount. 2. Includes supply current from regulators, supply monitor, and High Frequency Oscillator. 3. Includes supply current from regulators, supply monitor, and Low Frequency Oscillator. 						

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V_{VDDM}		2.60	2.65	2.70	V
Power-On Reset (POR) Threshold	V_{POR}	Rising Voltage on VDD	—	1.4	—	V
		Falling Voltage on VDD	0.75	—	1.36	V
VDD Ramp Time	t_{RMP}	Time to $V_{DD} > 2.7$ V	—	—	1	ms
Reset Delay from POR	t_{POR}	Relative to $V_{DD} > V_{POR}$	3	10	31	ms
Reset Delay from non-POR source	t_{RST}	Time between release of reset source and code execution	—	—	250	μ s
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	μ s
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	$F_{SYSCLK} > 1$ MHz	80	580	800	μ s
VDD Supply Monitor Turn-On Time	t_{MON}		—	—	100	μ s

4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time ¹	t_{WRITE}	One Byte	10	15	20	μ s
Erase Time ¹	t_{ERASE}	One Page	10	15	22.5	ms
V_{DD} Voltage During Programming ²	V_{PROG}		2.7	—	3.6	V
Endurance (Write/Erase Cycles)	N_{WE}		10k	100k	—	Cycles
CRC Calculation Time	t_{CRC}	One 256-Byte Block $SYSCLK = 48$ MHz	—	5.5	—	μ s
Note: <ol style="list-style-type: none"> 1. Does not include sequencing time before and after the write/erase operation, which may be multiple $SYSCLK$ cycles. 2. Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}). 3. Data Retention Information is published in the Quarterly Quality and Reliability Report. 						

4.1.8 ADC

Table 4.8. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N _{bits}		10			Bits
Throughput Rate	f _S		—	—	500	ksps
Tracking Time	t _{TRK}		300	—	—	ns
SAR Clock Frequency	f _{SAR}		—	—	8.33	MHz
Conversion Time	t _{CNV}	10-Bit Conversion,	13	—	—	Clocks
Sample/Hold Capacitor	C _{SAR}		—	30	—	pF
Input Mux Impedance	R _{MUX}		—	5	—	kΩ
Voltage Reference Range	V _{REF}		1	—	V _{DD}	V
Input Voltage Range ¹	V _{IN}	Single-Ended (AIN+ - GND)	0	—	V _{REF}	V
		Differential (AIN+ - AIN-)	-V _{REF}	—	V _{REF}	V
Power Supply Rejection Ratio	PSRR _{ADC}		—	70	—	dB
DC Performance, VREF = 2.4 V						
Integral Nonlinearity	INL		—	±0.5	±1	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL		—	±0.5	±1	LSB
Offset Error	E _{OFF}		-2	0	2	LSB
Offset Temperature Coefficient	TC _{OFF}		—	0.005	—	LSB/°C
Slope Error	E _M		—	-0.2	±0.5	%
Dynamic Performance 10 kHz Sine Wave Input 1dB below full scale, VREF = 2.4 V						
Signal-to-Noise	SNR		55	58	—	dB
Signal-to-Noise Plus Distortion	SNDR		55	58	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD		—	-73	—	dB
Spurious-Free Dynamic Range	SFDR		—	78	—	dB
Note:						
1. Absolute input pin voltage is limited by the VDD and GND supply pins.						

4.1.9 Voltage Reference

Table 4.9. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
On-chip Precision Reference						
Output Voltage	V_{REFP}	$T = 25\text{ }^{\circ}\text{C}$	2.38	2.42	2.46	V
Turn-on Time, settling to 0.5 LSB	t_{VREFP}	4.7 μF tantalum + 0.1 μF ceramic bypass on VREF pin	—	3	—	ms
		0.1 μF ceramic bypass on VREF pin	—	100	—	μs
Load Regulation	LR_{VREFP}	Load = 0 to 200 μA to GND	—	360	—	$\mu\text{V} / \mu\text{A}$
Short-circuit current	ISC_{VREFP}		—	—	8	mA
Power Supply Rejection	$PSRR_{VREFP}$		—	140	—	ppm/V
External Reference						
Input Current	I_{EXTREF}	Sample Rate = 500 ksps; $V_{REF} = 3.0\text{ V}$	—	9	—	μA

4.1.10 Temperature Sensor

Table 4.10. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Offset	V_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	764	—	mV
Offset Error ¹	E_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	15	—	mV
Slope	M		—	2.87	—	$\text{mV}/^{\circ}\text{C}$
Slope Error ¹	E_M		—	120	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity			—	0.5	—	$^{\circ}\text{C}$
Turn-on Time			—	1.8	—	μs
Note: 1. Represents one standard deviation from the mean.						

4.1.11 5 V Voltage Regulator

Table 4.11. 5V Voltage Regulator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input Voltage Range ¹	V _{REGIN}		2.7	—	5.25	V
Output Voltage on VDD ²	V _{REGOUT}	Output Current = 1 to 100 mA	3.0	3.3	3.6	V
Output Current ²	I _{REGOUT}		—	—	100	mA
Note: 1. Input range specified for regulation. When an external regulator is used, V _{REGIN} should be tied to VDD. 2. Output current is total regulator output, including any current required by the device.						

4.1.12 Comparators

Table 4.12. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	100	—	ns
		-100 mV Differential	—	250	—	ns
Response Time, CPMD = 11 (Low- est Power)	t_{RESP3}	+100 mV Differential	—	1.05	—	μs
		-100 mV Differential	—	5.2	—	μs
Positive Hysteresis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	-8	—	mV
		CPHYN = 10	—	-16	—	mV
		CPHYN = 11	—	-32	—	mV
Positive Hysteresis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysteresis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	-6	—	mV
		CPHYN = 10	—	-12	—	mV
		CPHYN = 11	—	-24	—	mV
Positive Hysteresis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysteresis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	-4.5	—	mV
		CPHYN = 10	—	-9	—	mV
		CPHYN = 11	—	-18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

4.3 Absolute Maximum Ratings

Stresses above those listed in [Table 4.18 Absolute Maximum Ratings on page 23](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at <http://www.silabs.com/support/quality/pages/default.aspx>.

Table 4.18. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VREGIN	V_{REGIN}		GND-0.3	5.8	V
Voltage on I/O, RSTb, or VBUS pins	V_{IN}	$V_{DD} > 2.2\text{ V}$	GND-0.3	5.8	V
		$V_{DD} < 2.2\text{ V}$	GND-0.3	$V_{DD}+3.6$	V
Total Current Sunk into Supply Pin	I_{VDD}		—	500	mA
Total Current Sourced out of Ground Pin	I_{GND}		500	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA

Note:

1. Exposure to maximum rating conditions for extended periods may affect device reliability.

4.4 Typical Performance Curves

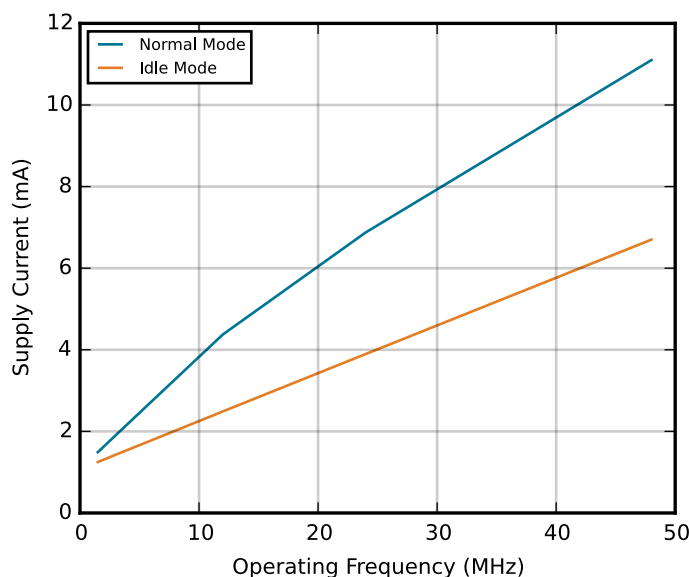


Figure 4.2. Typical Operating Supply Current using HFOSC0

Table 6.1. Pin Definitions for EFM8UB2x-QFP48

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.5	Multifunction I/O	Yes	UART0_RX INT0.5 INT1.5	
2	P0.4	Multifunction I/O	Yes	UART0_TX INT0.4 INT1.4	ADC0P.18 ADC0N.18 CMP0N.4
3	P0.3	Multifunction I/O	Yes	INT0.3 INT1.3	ADC0P.17 ADC0N.17 CMP0P.4
4	P0.2	Multifunction I/O	Yes	INT0.2 INT1.2	
5	P0.1	Multifunction I/O	Yes	INT0.1 INT1.1	
6	P0.0	Multifunction I/O	Yes	INT0.0 INT1.0	
7	GND	Ground			
8	D+	USB Data Positive			
9	D-	USB Data Negative			
10	VDD	Supply Power Input / 5V Regulator Output			
11	VREGIN	5V Regulator Input			
12	VBUS	USB VBUS Sense Input		VBUS	
13	RST / C2CK	Active-low Reset / C2 Debug Clock			
14	C2D	C2 Debug Data			
15	P4.7	Multifunction I/O		EMIF_D7 EMIF_AD7m	ADC0P.34 ADC0N.34
16	P4.6	Multifunction I/O		EMIF_D6 EMIF_AD6m	ADC0P.15 ADC0N.15 CMP1N.3
17	P4.5	Multifunction I/O		EMIF_D5 EMIF_AD5m	ADC0P.14 ADC0N.14 CMP1P.3

6.2 EFM8UB2x-QFP32 Pin Definitions

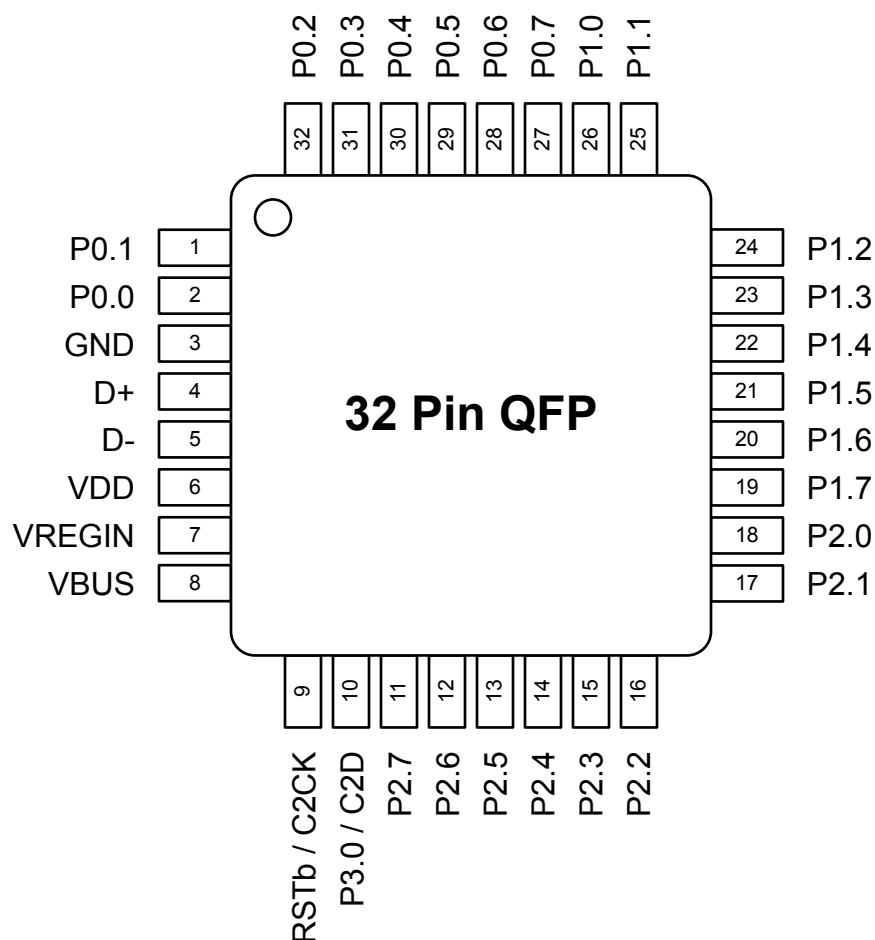


Figure 6.2. EFM8UB2x-QFP32 Pinout

Table 6.2. Pin Definitions for EFM8UB2x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	INT0.1 INT1.1	ADC0P.18 ADC0N.18 CMP0N.4
2	P0.0	Multifunction I/O	Yes	INT0.0 INT1.0	ADC0P.17 ADC0N.17 CMP0P.4
3	GND	Ground			
4	D+	USB Data Positive			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
5	D-	USB Data Negative			
6	VDD	Supply Power Input / 5V Regulator Output			
7	VREGIN	5V Regulator Input			
8	VBUS	USB VBUS Sense Input		VBUS	
9	RST / C2CK	Active-low Reset / C2 Debug Clock			
10	P3.0 / C2D	Multifunction I/O / C2 Debug Data	Yes		ADC0P.16 ADC0N.16
11	P2.7	Multifunction I/O	Yes		ADC0P.15 ADC0N.15
12	P2.6	Multifunction I/O	Yes		ADC0P.14 ADC0N.14
13	P2.5	Multifunction I/O	Yes		ADC0P.13 ADC0N.13 CMP0N.3
14	P2.4	Multifunction I/O	Yes		ADC0P.12 ADC0N.12 CMP0P.3
15	P2.3	Multifunction I/O	Yes		ADC0P.11 ADC0N.11 CMP1N.2
16	P2.2	Multifunction I/O	Yes		ADC0P.10 ADC0N.10 CMP1P.2
17	P2.1	Multifunction I/O	Yes		ADC0P.9 ADC0N.9 CMP0N.2
18	P2.0	Multifunction I/O	Yes		ADC0P.8 ADC0N.8 CMP0P.2
19	P1.7	Multifunction I/O	Yes		ADC0P.7 ADC0N.7 CMP1N.1

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
20	P1.6	Multifunction I/O	Yes		ADC0P.6 ADC0N.6 CMP1P.1
21	P1.5	Multifunction I/O	Yes		ADC0P.5 ADC0N.5 CMP0N.1
22	P1.4	Multifunction I/O	Yes		ADC0P.4 ADC0N.4 CMP0P.1
23	P1.3	Multifunction I/O	Yes		ADC0P.3 ADC0N.3 CMP1N.0
24	P1.2	Multifunction I/O	Yes		ADC0P.2 ADC0N.2 CMP1P.0
25	P1.1	Multifunction I/O	Yes		ADC0P.1 ADC0N.1 CMP0N.0
26	P1.0	Multifunction I/O	Yes		ADC0P.0 ADC0N.0 CMP0P.0
27	P0.7	Multifunction I/O	Yes	INT0.7 INT1.7	VREF
28	P0.6	Multifunction I/O	Yes	CNVSTR INT0.6 INT1.6	
29	P0.5	Multifunction I/O	Yes	INT0.5 INT1.5 UART0_RX	ADC0P.20 ADC0N.20 CMP1N.4
30	P0.4	Multifunction I/O	Yes	INT0.4 INT1.4 UART0_TX	ADC0P.19 ADC0N.19 CMP1P.4
31	P0.3	Multifunction I/O	Yes	EXTCLK INT0.3 INT1.3	

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
32	P0.2	Multifunction I/O	Yes	INT0.2 INT1.2	
Note: XTAL1 and XTAL2 are not available on this package. EXTCLK is still available on P0.3.					

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.0	Multifunction I/O	Yes	INT0.0 INT1.0	ADC0P.17 ADC0N.17 CMP0P.4
3	GND	Ground			
4	D+	USB Data Positive			
5	D-	USB Data Negative			
6	VDD	Supply Power Input / 5V Regulator Output			
7	VREGIN	5V Regulator Input			
8	VBUS	USB VBUS Sense Input		VBUS	
9	RST / C2CK	Active-low Reset / C2 Debug Clock			
10	P3.0 / C2D	Multifunction I/O / C2 Debug Data	Yes		ADC0P.16 ADC0N.16
11	P2.7	Multifunction I/O	Yes		ADC0P.15 ADC0N.15
12	P2.6	Multifunction I/O	Yes		ADC0P.14 ADC0N.14
13	P2.5	Multifunction I/O	Yes		ADC0P.13 ADC0N.13 CMP0N.3
14	P2.4	Multifunction I/O	Yes		ADC0P.12 ADC0N.12 CMP0P.3
15	P2.3	Multifunction I/O	Yes		ADC0P.11 ADC0N.11 CMP1N.2
16	P2.2	Multifunction I/O	Yes		ADC0P.10 ADC0N.10 CMP1P.2
17	P2.1	Multifunction I/O	Yes		ADC0P.9 ADC0N.9 CMP0N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P2.0	Multifunction I/O	Yes		ADC0P.8 ADC0N.8 CMP0P.2
19	P1.7	Multifunction I/O	Yes		ADC0P.7 ADC0N.7 CMP1N.1
20	P1.6	Multifunction I/O	Yes		ADC0P.6 ADC0N.6 CMP1P.1
21	P1.5	Multifunction I/O	Yes		ADC0P.5 ADC0N.5 CMP0N.1
22	P1.4	Multifunction I/O	Yes		ADC0P.4 ADC0N.4 CMP0P.1
23	P1.3	Multifunction I/O	Yes		ADC0P.3 ADC0N.3 CMP1N.0
24	P1.2	Multifunction I/O	Yes		ADC0P.2 ADC0N.2 CMP1P.0
25	P1.1	Multifunction I/O	Yes		ADC0P.1 ADC0N.1 CMP0N.0
26	P1.0	Multifunction I/O	Yes		ADC0P.0 ADC0N.0 CMP0P.0
27	P0.7	Multifunction I/O	Yes	INT0.7 INT1.7	VREF
28	P0.6	Multifunction I/O	Yes	CNVSTR INT0.6 INT1.6	
29	P0.5	Multifunction I/O	Yes	INT0.5 INT1.5 UART0_RX	ADC0P.20 ADC0N.20 CMP1N.4

Dimension	Min	Max
Note: <ol style="list-style-type: none"> 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. This Land Pattern Design is based on the IPC-7351 guidelines. 3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad. 4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release. 5. The stencil thickness should be 0.125 mm (5 mils). 6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads. 7. A No-Clean, Type-3 solder paste is recommended. 8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components. 		

7.3 QFP48 Package Marking

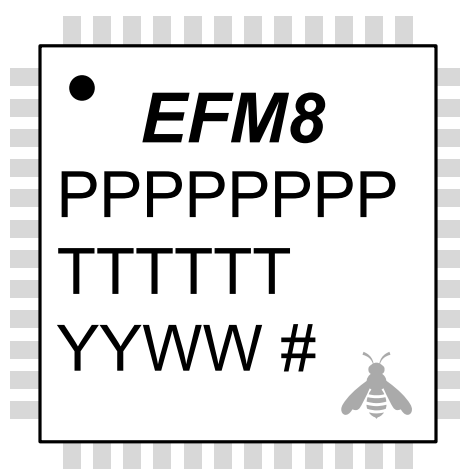


Figure 7.3. QFP48 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

Dimension	Min	Typ	Max
ddd	—	—	0.05
eee	—	—	0.08

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-220, variation VHHD except for custom features D2, E2, and L which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

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